Abstracts

Two Simple Methods for the Measurement of the Dielectric Permittivity of Low-Loss Microstrip Substrates (Short Papers)

R.M. Pannell and B.W. Jervis. "Two Simple Methods for the Measurement of the Dielectric Permittivity of Low-Loss Microstrip Substrates (Short Papers)." 1981 Transactions on Microwave Theory and Techniques 29.4 (Apr. 1981 [T-MTT]): 383-386.

Two simple methods are presented for the measurement of the dielectric permittivity of low-loss microstrip substrates. The permittivity associated with a specific length of microstrip may be obtained. The methods are not wasteful of substrate material.

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